

New Jersey Semi-Conductor Products, Inc.

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U.S.A.

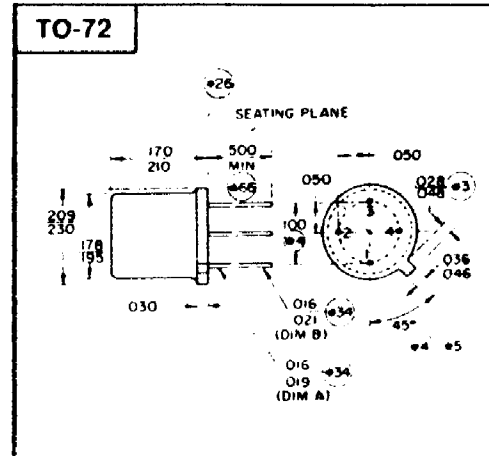
2N998
2N999
(SILICON)



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MAXIMUM RATINGS

Rating	Symbol	2N998	2N999	Unit
Collector-Emitter Voltage	V_{CEO}	60	60	Vdc
Collector-Base Voltage	V_{CB}	100	60	Vdc
Emitter-Base Voltage	V_{EB}		15	Vdc
Collector Current	I_C		500	mAdc
Total Device Dissipation @ $T_A = 25^\circ\text{C}$ Derate above 25°C	P_D		0.5 2.86	Watt mW/ $^\circ\text{C}$
Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C	P_D		1.8 10.3	Watts mW/ $^\circ\text{C}$
Operating Junction Temperature	T_J		+200	$^\circ\text{C}$
Storage Temperature Range	T_{stg}		-65 to +200	$^\circ\text{C}$



ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
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OFF CHARACTERISTICS

Collector-Emitter Sustaining Voltage* ($I_C = 30 \text{ mAdc}$, $I_E = 0$)	$BV_{CEO(sus)}$ *	60	—	Vdc
Collector-Base Breakdown Voltage ($I_C = 100 \mu\text{Adc}$, $I_E = 0$)	BV_{CBO}	100 60	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 100 \mu\text{Adc}$, $I_C = 0$)	BV_{EBO}	15	—	Vdc
Collector Cutoff Current ($V_{CB} = 80 \text{ Vdc}$, $I_E = 0$)	I_{CBO}	—	0.01	μAdc
($V_{CB} = 80 \text{ Vdc}$, $I_E = 0$, $T_A = 150^\circ\text{C}$)		—	15	
($V_{CB} = 60 \text{ Vdc}$, $I_E = 0$)		—	0.01	
($V_{CB} = 60 \text{ Vdc}$, $I_E = 0$, $T_A = 150^\circ\text{C}$)		—	10	
Emitter Cutoff Current ($V_{BE} = 10 \text{ Vdc}$, $I_C = 0$)	I_{EBO}	—	0.01	μAdc

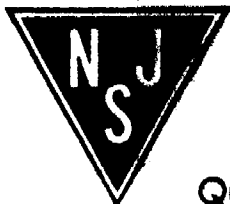
ON CHARACTERISTICS

DC Current Gain* ($I_C = 1 \text{ mAdc}$, $V_{CE} = 5 \text{ Vdc}$)	2N998	h_{FE} *	800	—	—
($I_C = 10 \text{ mAdc}$, $V_{CE} = 5 \text{ Vdc}$)	2N998		1,800	8,000	
($I_C = 100 \text{ mAdc}$, $V_{CE} = 5 \text{ Vdc}$)	2N998	2,000	—		
($I_C = 0.1 \text{ mAdc}$, $V_{CE} = 10 \text{ Vdc}$)	2N999	1,000	—		
($I_C = 10 \text{ mAdc}$, $V_{CE} = 10 \text{ Vdc}$)	2N999	4,000	—		
($I_C = 100 \text{ mAdc}$, $V_{CE} = 10 \text{ Vdc}$)	2N999	7,000	70,000		
($I_C = 100 \text{ mAdc}$, $V_{CE} = 10 \text{ Vdc}$, $T_A = -55^\circ\text{C}$)	2N999	1,000	—		
($I_C = 10 \text{ mAdc}$, $V_{CE} = 5 \text{ Vdc}$, measured across each transistor within the device)	2N998	25	—		
($I_C = 10 \text{ mAdc}$, $V_{CE} = 10 \text{ Vdc}$, measured across each transistor within the device)	2N999	25	—		

DYNAMIC CHARACTERISTICS

Output Capacitance ($V_{CB} = 10 \text{ Vdc}$, $I_E = 0$, $f = 140 \text{ kHz}$)	2N998 2N999	C_{ob}	— —	30 20	pF
Input Capacitance ($V_{BE} = 0.5 \text{ Vdc}$, $I_C = 0$, $f = 140 \text{ kHz}$)	2N998 2N999	C_{ib}	— —	50 10	pF
Small-Signal Current Gain ($I_C = 1 \text{ mAdc}$, $V_{CE} = 5 \text{ Vdc}$, $f = 1 \text{ kHz}$)	2N998	h_{fe}	1,000	—	—
Noise Figure** ($I_C = 0.1 \text{ mAdc}$, $V_{CE} = 10 \text{ Vdc}$, $R_g = 5 \text{ kohms}$, $f = 1 \text{ kHz}$, Bandwidth = 200 Hz)	2N998	NF^{**}	—	6	dB

*Pulse Test: Pulse Width = 300 μs , Duty Cycle = 1%



Quality Semi-Conductors